



Bi-Directional N-Channel 20-V (D-S) MOSFET

PRODUCT SUMMARY		
V_{S1S2} (V)	$r_{S1S2(on)}$ (Ω)	I_{S1S2} (A)
20	0.045 @ $V_{GS} = 4.5$ V	5.0
	0.048 @ $V_{GS} = 3.7$ V	4.8
	0.057 @ $V_{GS} = 2.5$ V	4.4
	0.072 @ $V_{GS} = 1.8$ V	3.9

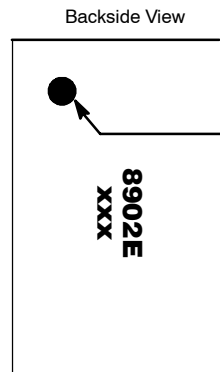
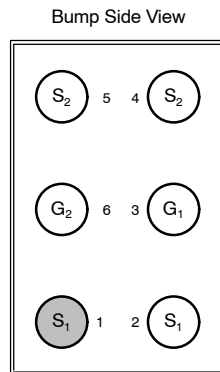
FEATURES

- TrenchFET® Power MOSFET
- Ultra-Low $r_{SS(on)}$
- ESD Protected: 4000 V
- New MICRO FOOT® Chipscale Packaging Reduces Footprint Area, Profile (0.65 mm) and On-Resistance Per Footprint Area

APPLICATIONS

- Battery Protection Circuit
 - 1-2 Cell Li+/LiP Battery Pack for Portable Devices

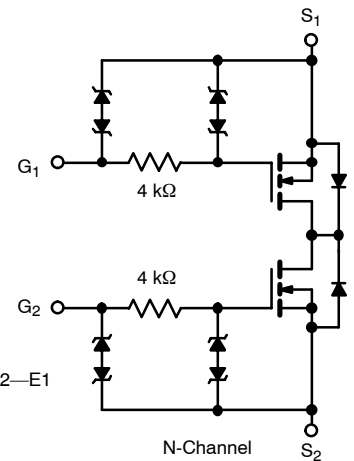
MICRO FOOT



Pin 1 Identifier

Device Marking:
8902E = P/N Code
xxx = Date/Lot Traceability Code

Ordering Information: Si8902EDB-T2—E1



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)				
Parameter	Symbol	5 secs	Steady State	Unit
Source1—Source2 Voltage	V_{S1S2}	20		V
Gate-Source Voltage	V_{GS}	± 12		
Continuous Source1—Source2 Current ($T_J = 150^\circ\text{C}$) ^a	I_{S1S2}	$T_A = 25^\circ\text{C}$	5.0	A
		$T_A = 85^\circ\text{C}$	3.4	
Pulsed Source1—Source2 Current	I_{SM}	40		
Maximum Power Dissipation ^a	P_D	$T_A = 25^\circ\text{C}$	1.7	W
		$T_A = 85^\circ\text{C}$	0.8	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to 150		$^\circ\text{C}$
Package Reflow Conditions ^c	VPR	215		
	IR/Convection	220		

THERMAL RESISTANCE RATINGS				
Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^a	R_{thJA}	$t \leq 5$ sec	60	$^\circ\text{C/W}$
		Steady State	95	
Maximum Junction-to-Foot ^b	R_{thJF}	18	22	

Notes

- Surface Mounted on 1" x 1" FR4 Board.
- The Foot is defined as the top surface of the package.
- Refer to IPC/JEDEC (J-STD-020A), no manual or hand soldering.



SPECIFICATIONS (T_J = 25 °C UNLESS OTHERWISE NOTED)

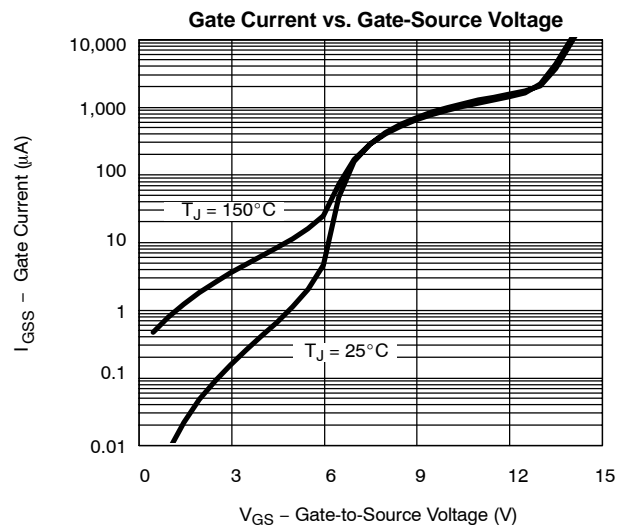
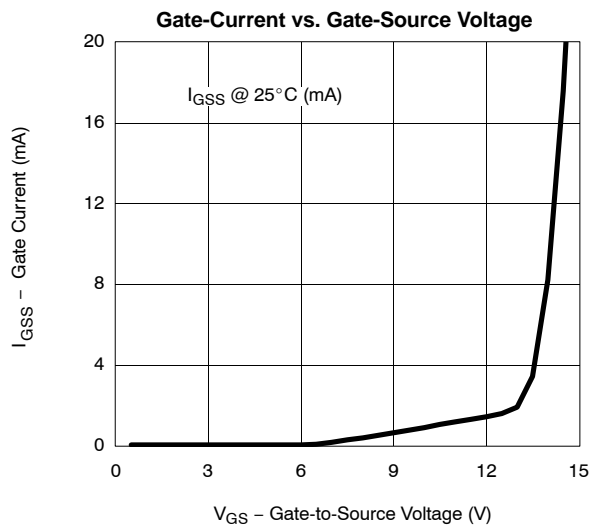
Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Gate Threshold Voltage	V _{GS(th)}	V _{SS} = V _{GS} , I _D = 980 μA	0.45		1.0	V
Gate-Body Leakage	I _{GSS}	V _{SS} = 0 V, V _{GS} = ± 4.5 V			± 4	μA
		V _{SS} = 0 V, V _{GS} = ± 12 V			± 10	mA
Zero Gate Voltage Source Current	I _{S1S2}	V _{SS} = 20 V, V _{GS} = 0 V			1	μA
		V _{SS} = 20 V, V _{GS} = 0 V, T _J = 85 °C			5	
On-State Source Current ^a	I _{S(on)}	V _{SS} = 5 V, V _{GS} = 4.5 V	5			A
Source1—Source2 On-State Resistance ^a	r _{S1S2(on)}	V _{GS} = 4.5 V, I _{SS} = 1 A		0.038	0.045	Ω
		V _{GS} = 3.7 V, I _{SS} = 1 A		0.041	0.048	
		V _{GS} = 2.5 V, I _{SS} = 1 A		0.048	0.057	
		V _{GS} = 1.8 V, I _{SS} = 1 A		0.060	0.072	
Forward Transconductance ^a	g _{fs}	V _{SS} = 10 V, I _{SS} = 1 A		20		S
Dynamic^b						
Turn-On Delay Time	t _{d(on)}	V _{SS} = 10 V, R _L = 10 Ω I _{SS} ≅ 1 A, V _{GEN} = 4.5 V, R _G = 6 Ω		1	1.5	μs
Rise Time	t _r			3	4.5	
Turn-Off Delay Time	t _{d(off)}			17	26	
Fall Time	t _f			10	15	

Notes

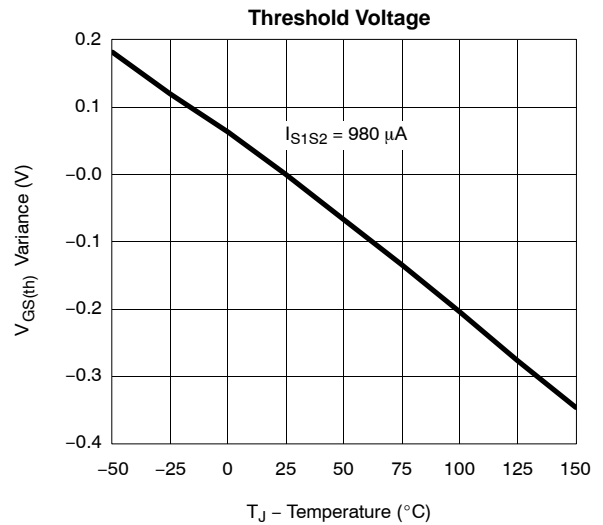
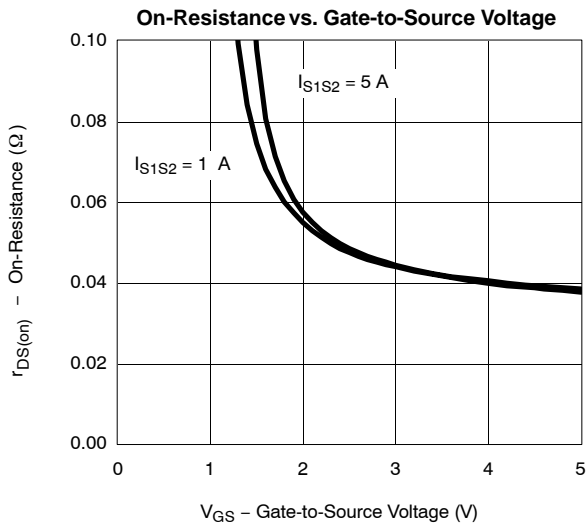
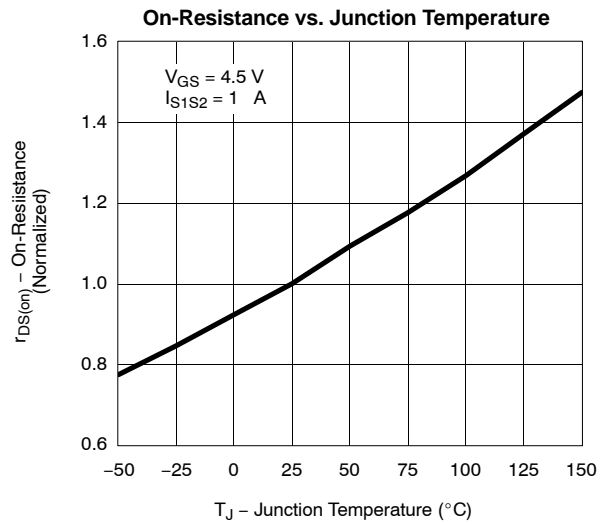
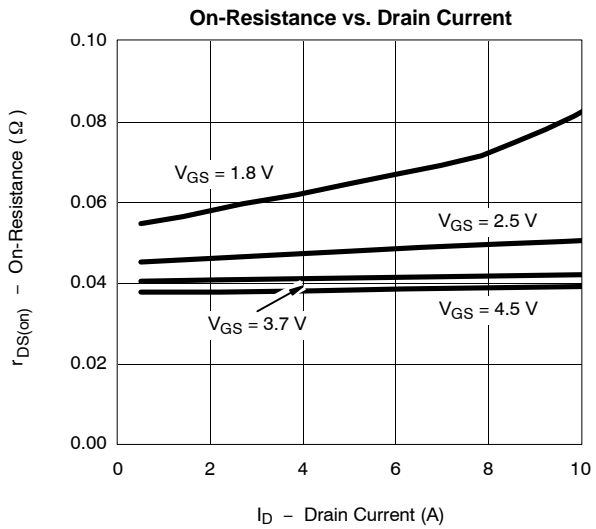
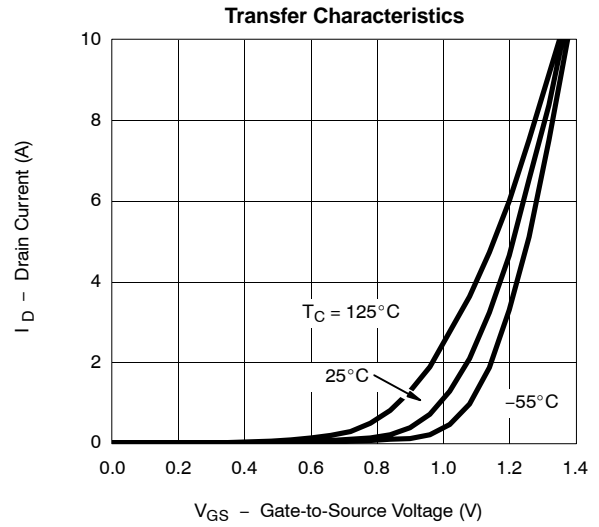
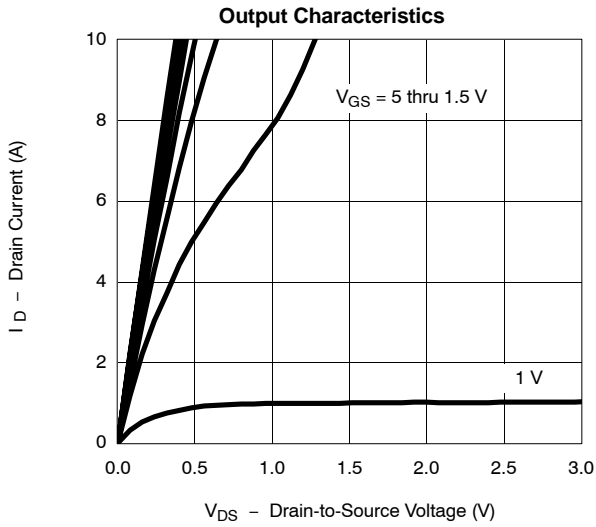
- a. Pulse test; pulse width ≤ 300 μs, duty cycle ≤ 2%.
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

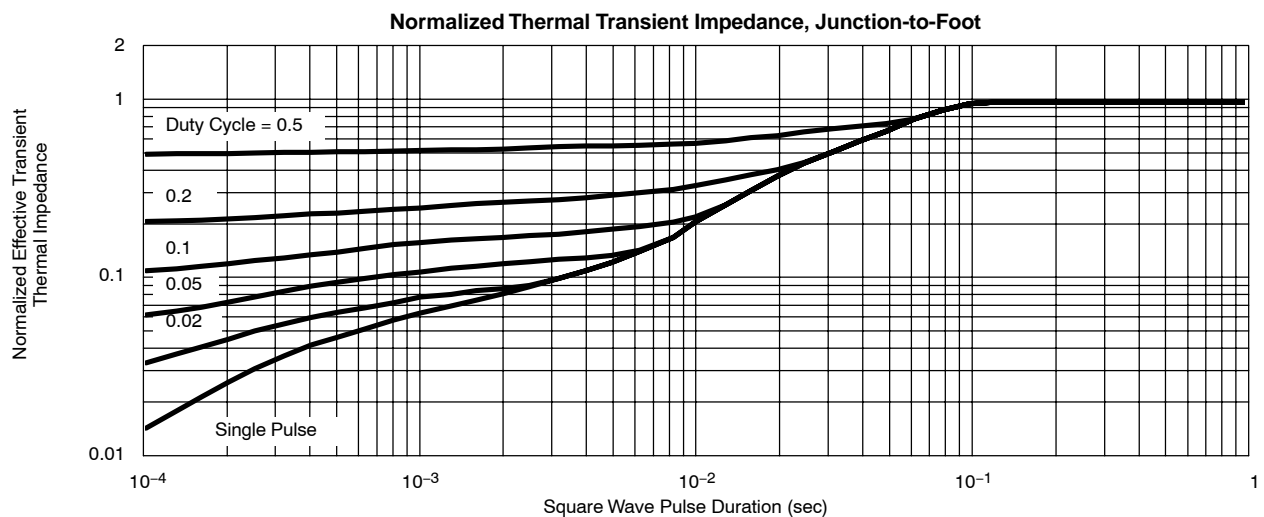
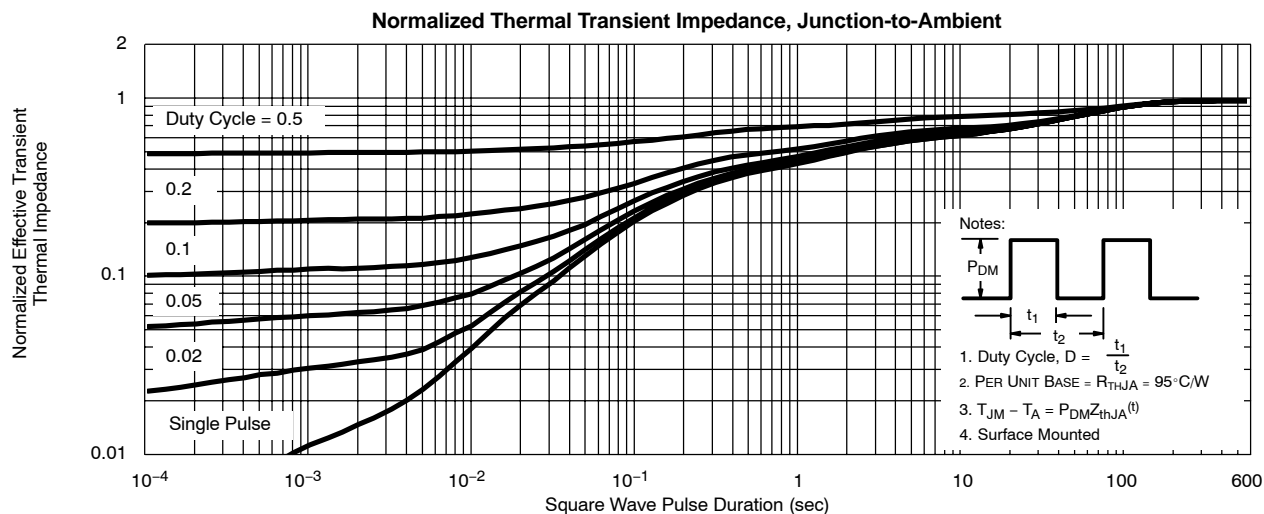
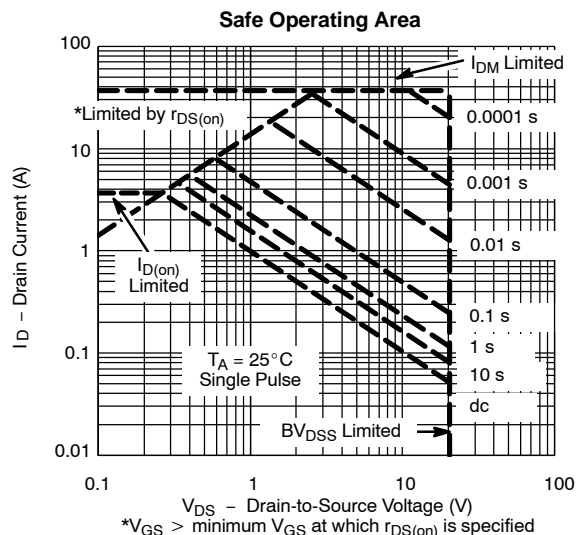
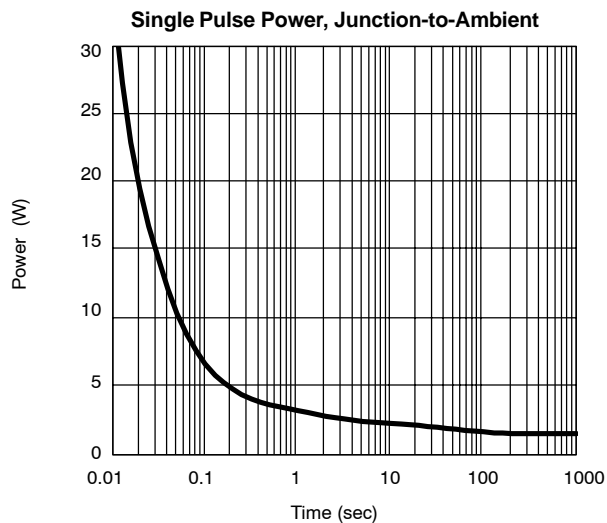
TYPICAL CHARACTERISTICS (25 °C UNLESS NOTED)



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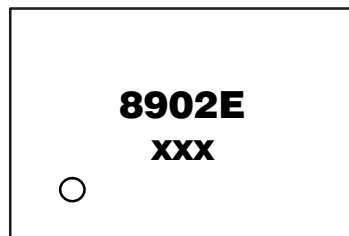
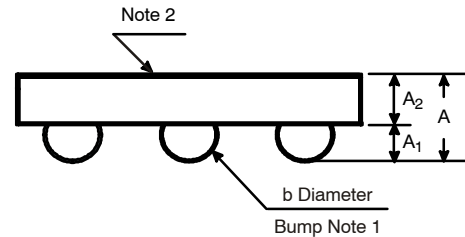
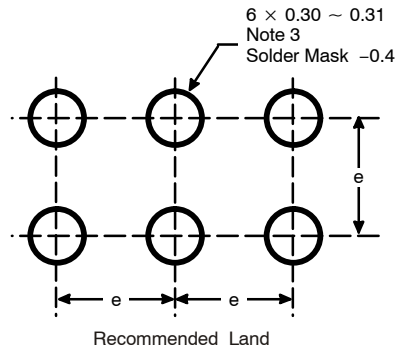


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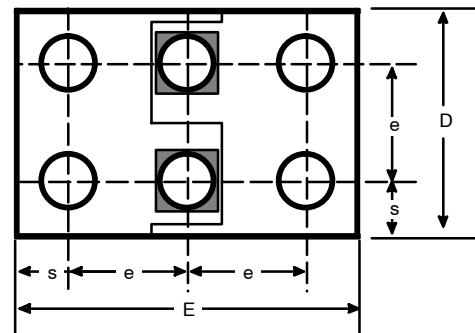


PACKAGE OUTLINE

MICRO FOOT: 6-BUMP (2 X 3, 0.8-mm PITCH)



Mark on Backside of Die



NOTES (Unless Otherwise Specified):

1. 6 solder bumps are Eutetic 63Sn/37Pb with diameter 0.37 – 0.41 mm
2. Backside surface is coated with a Ag/Ni/Ti layer
3. Non-solder mask defined copper landing pad.
4. Laser marks on the silicon die back

Dim	MILLIMETERS*		INCHES	
	Min	Max	Min	Max
A	0.600	0.650	0.0236	0.0256
A ₁	0.260	0.290	0.102	0.114
A ₂	0.340	0.360	0.0134	0.0142
b	0.370	0.410	0.0146	0.0161
D	1.520	1.600	0.0598	0.0630
E	2.320	2.400	0.0913	0.0945
e	0.750	0.850	0.0295	0.0335
s	0.380	0.400	0.0150	0.0157

* Use millimeters as the primary measurement.

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